

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12900-001001	Application No. 09/845,178
		Applicant Zhonghua Lu et al.	
		Filing Date April 27, 2001	Group Art Unit 1746

Information Disclosure Statement
by Applicant
(Use several sheets if necessary)

(37 CFR §1.98(b))

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
mzw	AA	6,589,499	7/8/03	Gao et al.			
	AB	6,620,400	9/16/03	Gao et al.			
	AC	6,361,756	3/26/02	Gao et al.			
	AD	2003/3082452	5/1/03	Ueda et al.			
	AE	5,993,998	11/30/99	Yasuda			
	AF	6,103,422	8/15/00	Kanai			
	AG	5,609,975	3/11/97	Hasegawa et al.			
	AH	5,292,601	3/8/94	Sugeno et al.			
	AI	2002/053663	5/9/02	Ito et al.			
	AJ	6,214,493	4/10/01	Bruce et al.			
	AK	6,077,496	6/20/00	Ito et al.			
	AL	5,478,671	12/26/95	Idota			
	AM	5,626,635	5/6/97	Yamaura et al.			
	AN	6,589,694	7/8/03	Gosho et al.			
	AO	2002/0150530	10/17/02	Gao et al.			
	AP	6,040,090	3/21/00	Sunagawa et al.			
	AQ	5,478,675	12/26/95	Nagaura et al.			
	AR	2002/0086210	11/8/01	Naruoka et al.			
	AS	6,551,744	4/22/03	Ohzuku et al.			
	AT	6,017,654	1/25/00	Kumta et al.			
	AU	2001/0010807	8/2/01	Matsubara			
	AV	5,981,445	11/9/99	Kirchnerova et al.			
	AW	5,531,920	7/2/96	Mao et al.			
	AX	5,565,688	10/15/96	Hayashi			
	AY	5,742,070	4/21/98	Hayashi et al.			
	AZ	5,770,173	6/23/98	Nitta et al.			
mzw	AAA	5,589,300	12/31/96	Fauteux et al.			

Examiner Signature <i>M. Z. Lu</i>	Date Considered <i>3/31/05</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

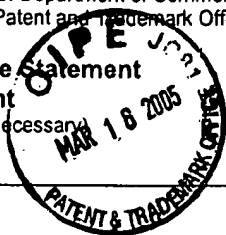
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U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
MRJ	ABB	5,370,948	12/6/94	Hasegawa et al.			
	ACC	5,264,201	11/23/93	Dahn et al.			
	ADD	5,911,920	6/15/99	Hasezaki et al.			
	AEE	5,521,027	5/28/96	Okuno et al.			
MRJ	AFF	5,525,443	5/11/96	Okuno et al.			
	AGG						

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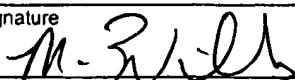
Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
m	AHH	JP2822659		Japan			X	
	AII	JP05-067466	3/19/1993	Japan			X	
	AJJ	JP05-182667	7/23/1993	Japan			X	
	AKK	JP05-198301	8/6/1993	Japan			X	
	ALL	JP05-283077	10/29/1993	Japan			X	
	AMM	JP06-275264	9/30/1994	Japan			X	
	ANN	JP06-275269	9/30/1994	Japan			X	
	AOO	JP07-134985	5/23/1995	Japan			X	
	APP	JP07-235291	9/5/1995	Japan			X	
	AQQ	JP07-235292	9/5/1995	Japan			X	
	ARR	JP08-171935	7/2/1996	Japan			X	
	ASS	JP08-315819	11/29/1996	Japan			X	
	ATT	JP10-188982	7/21/1998	Japan			X	
	AUU	JP2000-173599	6/23/2000	Japan			X	
	AVV	JP2000-173667	6/23/2000	Japan			X	
	AWW	JP2000-195514	7/14/2000	Japan			X	
	AXX	JP2000-231919	8/22/2000	Japan			X	
	AYY	JP2000-323123	11/24/2000	Japan			X	
	AZZ	JP2000-323142	11/24/2000	Japan			X	
	AAAA	JP2000-327339	11/28/2000	Japan			X	
m	ABBB	JP2001-052702	2/23/2001	Japan			X	
	ACCC	JP86055747	3/31/1980	Japan			X	
	ADDD	JP3079382		Japan			X	
	AEEE	JP2668678		Japan			X	

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							Yes	No
M	AFFF	JP2561556		Japan			X	
	AGGG	JP2699176		Japan			X	
	AHHH	JP8-213015	8/20/1996	Japan			X	
	AIII	JP 10-1065652		Japan			X	
	AJJJ	2001-146426		Japan			X	
	AKKK	2000-268821		Japan			X	
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	AMMM	8-37007	1996	Japan			X	
	ANNN	2000-277151		Japan			X	
	AOOO	2000-223157	8/11/2000	Japan			X	
	APPP	2000-294242	10/20/00	Japan			X	
	AQQQ	2000-294240		Japan			X	
	ARRR	2002-063900	2/28/2002	Japan			X	
	ASSS	EP1 117 145	7/18/2001	EPO				
	ATTT	EP 0 501 187	4/17/1996	EPO				
M	AUUU	EP 0 903 796	3/24/99	EPO				

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M	AVVV	Numata, K. et al., <i>Preparation and electrochemical properties of layered lithium-cobalt-manganese oxides</i> , <i>Solid State Ionics</i> , 118(1999) pp. 117-120.
M	AWWW	Numata K. et al., <i>Synthesis of Solid Solutions in a System of LiCoO₂-Li₂MnO₃ for Cathode Materials of Secondary Lithium Batteries</i> , <i>The Chemical Society of Japan</i> , (1997), pp. 725-726.
M	AXXX	Numata K. et al, <i>Synthesis and characterization of layer structured solid solutions in the system of LiCoO₂-Li₂MnO₃</i> , <i>Solid State Ionics</i> 117 (1999) pp. 257-263.

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